



In place of PTO-1449 Form	U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			Complete if Known											
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			<table border="1"> <tr> <td>Application Number</td> <td>10/706,735</td> </tr> <tr> <td>Filing Date</td> <td>November 12, 2003</td> </tr> <tr> <td>Applicant(s)</td> <td>Wayne A. Weimer</td> </tr> <tr> <td>Art Unit</td> <td>1743</td> </tr> <tr> <td>Examiner Name</td> <td>To Be Determined</td> </tr> </table>			Application Number	10/706,735	Filing Date	November 12, 2003	Applicant(s)	Wayne A. Weimer	Art Unit	1743	Examiner Name	To Be Determined
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SHEET	1	OF	2	Attorney/Docket Number	34003.31										

U. S. PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Document Number (Country Code - Number - Kind)	Publication Date (MM-DD-YYYY)	Name of Patentee or Applicant of Cited Document	Translation YN
HEA	AA	5,567,628	10-22-1996	Tarcha, et al.	
HEA	AB	5,609,907	03-11-1997	Natan	
HEA	AC	5,939,021	08-17-1999	Hansen, et al.	
HEA	AD	5,991,488	11-23-1999	Salamon, et al.	
HEA	AE	6,025,202	02-15-2000	Natan	
HEA	AF	6,608,716	08-19-2003	Armstrong, et al.	

FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date (MM-DD-YYYY)	Patentee or Applicant of Cited Document	Translation YN
A SA	AG	WO 98/04902	02-05-1998	The University of Oregon, et al.	

OTHER PRIOR ART					
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume, issue number(s), publisher, city/country where published			
HEA	AH	Campion, Alan, et al., "Surface-Enhanced Raman Scattering", Chemical Society Reviews, Vol. 27, 1998, pp. 241-250.			
HEA	AI	Gotschy, W., et al., "Thin Films by Regular Patterns of Metal Nanoparticles: Tailoring the Optical Properties by Nanodesign", Applied Physics B, 1996, pp. 381-384.			
HEA	AJ	Haynes, Christy L., et al., "Nanosphere Lithography: A Versatile Nanofabrication Tool for Studies of Size-Dependent Nanoparticle Optics", J. Phys. Chem. B, Vol. 105, No. 24, 2001, pp. 5599-5611.			
HEA	AK	Hulteen, John C., et al., "Nanosphere Lithography: Size-Tunable Silver Nanoparticle and Surface Cluster Arrays", J. Phys. Chem. B, Vol. 103, No. 19, 1999, pp. 3854-3863.			
HEA	AL	Jensen, Traci R., et al., "Nanosphere Lithography: Effect of the External Dielectric Medium on the Surface Plasmon Resonance Spectrum of a Periodic Array of Silver Nanoparticles", J. Phys. Chem. B, Vol. 103, No. 45, 1999, pp. 9846-9853.			
HEA	AM	Jensen, Traci R., et al., "Nanosphere Lithography: Surface Plasmon Resonance spectrum of a Periodic Array of Silver Nanoparticles by Ultraviolet - Visible Extinction Spectroscopy and Electrodynamic Modeling", J. Phys. Chem. B, Vol. 103, No. 13, 1999, pp. 2394-2401.			
HEA	AN	Jensen, Traci R., et al., "Nanosphere Lithography: Tunable Localized Surface Plasmon Resonance Spectra of Silver Nanoparticles", J. Phys. Chem. B., Vol. 104, No. 45, 2000, pp.10549-10556.			
HEA	AO	Kim, W., et al., "Fractals in Microcavities: Giant Coupled, Multiplicative Enhancement of Optical Responses", Physical Review Letters, Vol. 82, Issue 24, June 14, 1999, pp. 4811-4814.			
HEA	AP	Kneipp, Katrin, et al., "Single Molecule Detection Using Surface-Enhanced Raman Scattering (SERS)", Physical Review Letters, Vol. 78, No. 9, March 3, 1997, pp. 1667-1670.			

Examiner Signature	<i>Wayne A. Weimer</i>	Date Considered	5/16/05
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SHEET	2	OF	2	Attorney/Docket Number
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HEA	AQ	Levlin, M., et al., "Evaporation of Gold Thin Films on Mica: Effect of Evaporation Parameters", Applied Surface Science 115, 1997, pp. 31-38		
HEA	AR	Levlin, M., et al., "Evaporation of Silver Thin Films on Mica", Applied Surface Science 171, 2001, pp. 257-264		
HEA	AS	Link, Stephan, et al., "Shape and Size Dependence of Radiative, Non-Radiative and Photothermal Properties of Gold Nanocrystals", Int. Reviews in Physical Chemistry, Vol. 19, No. 3, 2000, pp. 409-453.		
AEA	AT	Malinsky, Michelle Duval, et al., "Chain Length Dependence and Sensing Capabilities of the Localized Surface Plasmon Resonance of Silver Nanoparticles Chemically Modified with Alkanethiol Self-Assembled Monolayers", J. Am. Chem. Soc., Vol. 123, No. 7, 2001, pp. 1471-1482.		
AEA	AU	Malinsky, Michelle Duval, et al., "Nanosphere Lithography: Effect of Substrate on the Localized Surface Plasmon Resonance Spectrum of Silver Nanoparticles", J. Phys. Chem. B., Vol. 105, No. 12, 2001, pp. 2343-2350.		
AEA	AV	Mulvaney, Shawn P., et al., "Raman Spectroscopy", Analytical Chemistry, Vol. 72, No. 12, June 15, 2000, pp. 145R-157R.		
HEA	AW	Nie, Shuming, et al., "Probing Single Molecules and Single Nanoparticles by Surface-Enhanced Raman Scattering", Science, Vol. 275, February 21, 1997, pp. 1102-1106.		
HEA	AX	Schlegel, Vicki L., et al., "Silver-Island Films as Substrates for Enhanced Raman Scattering: Effect of Deposition Rate on Intensity", Analytical Chemistry, Vol. 63, No. 3, February 1, 1991, pp. 241-247.		
HEA	AY	Van Duyne, R. P., et al., "Atomic Force Microscopy and Surface-Enhanced Raman Spectroscopy. I. Ag Island Films and AG Film Over Polymer Nanosphere Surfaces Supported on Glass", J. Chem. Phys., Vol. 99, No. 3, August 1, 1993, pp. 2101-2115.		
HEA	AZ	Weimer, W. A., et al., "Tunable Surface Plasmon Resonance Silver Films", Applied Physics Letters, Vol. 79, No. 19, November 5, 2001, pp. 3164-3166.		

Examiner Signature		Date Considered	5/10/05
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AES	0 646 660 A1		4/1995	Kodak Limited

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HEA		Sennett, R. S. et al., "The Structure of Evaporated Metal Films and Their Optical Properties," Journal of the Optical Society of America, Vol. 40, No. 4, April 1950, pp. 203-211.				

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